Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	Applicant(s)/Patent under Reexamination	
10/002,063	GURSKI ET AL.		
Examiner	Art Unit		
Thien D. Tran	2665		

SEARCHED					
Class	Subclass	Date	Examiner		
		r			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
370	520	3/12/2006	TT		
	514	3/12/2006	ΤΤ		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPGPUB, USPAT, USOCR, EPO, DERWENT) 370/320, 342, 441, 514, 520	3/12/2006	π		
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